

SMIS130804 Series Ultra-high current SMT power inductors





◆特征:

- 低直流电阻和超大电流的薄型设计
- 磁屏蔽型抗电磁干扰强适用于高密度安装
- 高可靠性,通过采用一体成型结构享有卓越 的抗震动性
- 由于复合结构, 超低蜂鸣噪声
- 低损耗合金粉末压铸低阻抗,小寄生电容
- 能效高,可减少绕线的低直流电阻与磁芯的 涡流损耗
- 频率高达 3MHz
- 绝缘最大电压 30VDC
- 符合 RoHS,无卤和 REACH

◆用途:

- PDA,笔记本,台式机,服务器应用程序
- 大电流 POL 转换器
- 电池供电设备
- 分布式电源系统中的 DC/DC 转换器

◆环境:

工作温度: -55℃ 至+125℃
 (包括线圈自身温升)

◆试验设备:

- 电感值: WK3260B 或同等仪器
- 电流: WK3260B+WK3265B
- 直流电阻: Chroma 16502 或同等仪器

◆产品型号:

SMIS

1

•	9
1	-%
,,,,	类型 Type
19.11	成型贴片功率电感
SMIS	Molding SMT Power Inductor

Features:

- Low RDC and ultra-high current thin design
- Magnetic shielding type, strong anti- electromagnetic
 Interference, suitable for high- density installation
- High-reliability, High vibration resistance as result of newly developed integral construction
- Ultra Low buzz noise, due to composite construction
- Die-casting by low loss alloy powder low impedance,
 Small parasitic capacitance
- High efficiency Low DC resistance of winding and low eddy-current loss of the core
- Frequency up to 3MHz
- Absolute maximum voltage 30VDC
- RoHS, Halogen Free and REACH Compliance

Applications:

- PDA , notebook ,desktop ,server applications
- High current POL converters
- Battery powered devices
- DC/DC converters in distributed power systems

Environmental Data:

• Operating Temperature: -40° C to +125 $^{\circ}$ C (Including coils self-temperature rise)

Test Equipment:

- L: WK3260B LCR meter or equivalent
- Isat & Irms: WK3260B+WK3265B
- DCR:Chroma 16502 or equivalent

Product Identification:

	2 ×					
	外形尺寸(L×W×H) (mm)					
	External Dimensions (L×W×H)					
1	(mm)					
1	130804	12.8×7.8×4.2				

R15

Inductance
0.15 uH

30804

(5)



4

公差 Inductance Tolerance

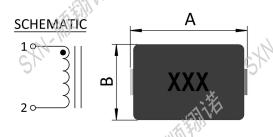
J:±5%,K: ±10%, L: ±15%

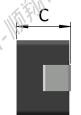
M: ±20%,P: ±25%, N: ±30%

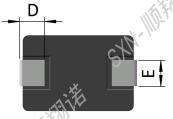
(5)		9		
	包装 Packing			
B 散装Bulk Package				
TF 编带Tape & Reel				

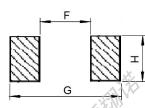
◆外观尺寸:

Shape and Dimensions (dimensions are in mm):









Recommended

Co-planarity: 0.15Max

Part No				ITEM				
	Α	В	С	D	E	F	G	Н
SMIS130804	12.80	7.80	4.20	3.50	2.50	6.00	14.50	5.00
31/113 130004	±0.40	±0.40	Max	±0.50	±0.50	Тур	Тур	Тур

◆规格特性:

Specifications:

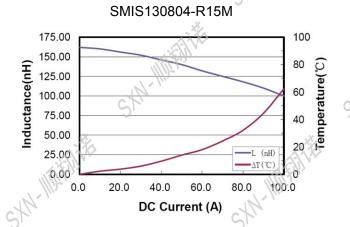
SMIS130804 Series Electrical Characteristics (Electrical specifications at 25[°]C)

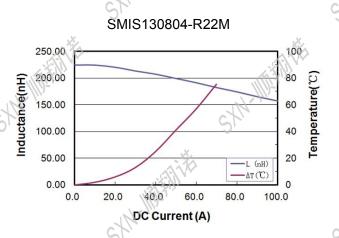
Part No ¾	Inductance 100KHz 1.0V		DCR	(mΩ)	Saturation Current	Temperature Rise Current
Part No.	L(μH) '@0A	Tol	Typical	Max	(A) Typical	(A) Typical
SMIS130804-R15M	0.15	±20%	0.41	0.55	85.00	45.00
SMIS130804-R22M	0.22	±20%	0.45	0.60	80.00	45.00
SMIS130804-R33M	0.33	±20%	1.12	1.30	70.00	35.00
SMIS130804-R47M	0.47	±20%	1.12	1.30	60.00	35.00

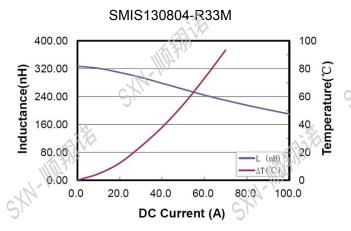
- Saturation Current: DC current at which inductance drops 30% from its value without current.
- Temperature Rise Current: the actual value of DC current when the temperature rise is ΔT 40 °C (Ta=25 °C).
- Rated DC Current: The less value which is Isat or Irms.
- Special remind Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.



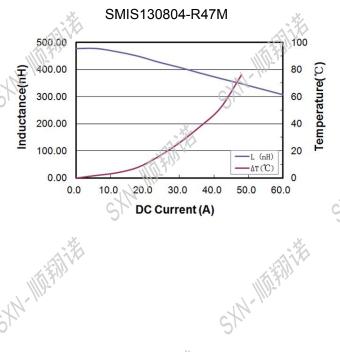
Saturation current VS temperature rise current curve







SXN-IIII FI



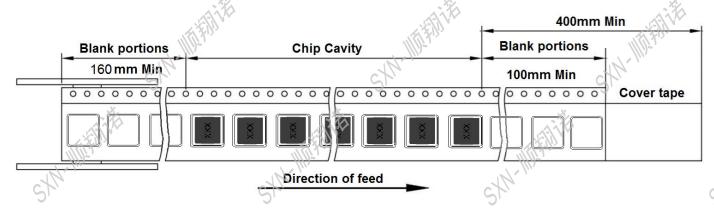
SAN-III. SAN-IIII. SAN-IIIIII. SAN-IIII. SAN-I

SXV-IIII: Filiti

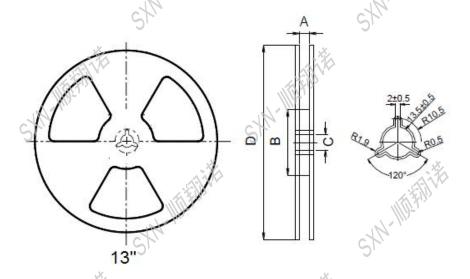


◆产品包装: Packaging:

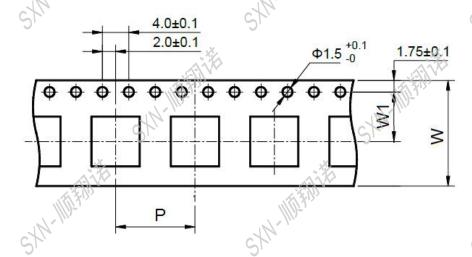
• Tape and Reel Specifications: (Dimensions are in mm)



Reel dimensions (mm)



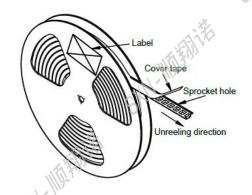
●Tape Dimension (mm)



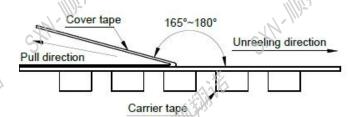
SXN-IIII 持持港



• Cover tape peel off condition

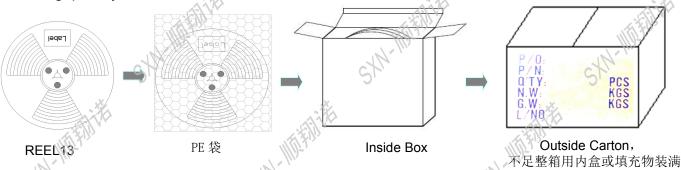


- a) Cover tape peel force shall be 10 to 120g
- b) Noodle strip peeling angle165°to 180°



Packing quantity

SMIIIFAITE



K	Dort No	Тар	e Dimen	sion		Reel Din	nensions	í.	REEL	Inside	Outside
	Part No.	W	P	W1	Α	В	С		(PCS)	Box(PCS)	Carton(PCS)
	SMIS130804	24.0	12.0	11.5	24.4	60	13	330	1000	2000	6000
		X.	,			х.	7	·		'ن ک	
		(A)									
	M. Illin					William			1/10		
	SKI				SKI				Str		
X,				X.					×		. v

SXN-IIII Filit

SKN-IIII jājā tili

SWIIIIijijijiji



◆可靠性测试: Reliability Testing:

◆ り 靠性 测试:	<u>ch</u>	Reliability resting:			
Items	Requirements	Test Methods and Remarks			
Terminal Strength Reference docu ments: GB/T 2423.60-2008 端子強度(SMT)	1. Pulling test: Define. A: sectional area of terminal A ≤ 8mm2 force ≥ 5N time:30sec 8mm2 <a 10n="" 10sec="" 2.="" 20mm2="" 20mm2<a="" 20n="" 3.="" above="" any="" force="" loose="" meet="" paste="" requirements="" solder="" td="" terminal<="" the="" thickness:0.12mm="" time:="" without="" ≤="" ≥=""><td>Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.</td>	Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.			
-511		- 5/h			
erminal Strength Reference docu ments: GB/T 2423.60-2008 端子強度(DIP)	1.Terminal diameter(d) mm 0.35 < d ≤ 0.50 Applied force:5N Duration: 10sec2.Terminal diameter(d) mm0.50 < d ≤ 0.80 Applied force:10N Duration: 10sec3.Terminal diameter(d) mm0.80 < d ≤ 1.25 Applied force:20N Duration: 10sec4.Terminal diameter(d) mmD > 1.25 Applied force:40N Duration. 10sec5.Meet the above requirements without any loose terminal.	Pull Force:the force shall be applied gradually to the terminal and thenmaintained for 10 seconds. Pulling test			
2,	1.No visible mechanical damage.	1.Solder the inductor to the test jig (glass epoxy			
Decistance to Flowers		board 2.shown in Using a leadfree solder. Then apply a force in the direction shown 3.Flexure: 2mm.			
Resistance to Flexure JIS C 5321:1997	Str. Str.	4.Pressurizing Speed: 0.5mm/sec.			
抗弯曲性试验	SKN-IIII FAITH	5.Keep time: 30 sec. R230 Flexure			
Dropping	1.No case deformation or change	1.Drop the packaged products from 1m high in 1			
Reference documents:	inappearance.	angle, 3 ridges and 6surfaces, twice in each			
GB/T 2423.7-2018	2.No short and no open.	direction.			
落下試驗	D' 3'	on estion.			
	1 No visible mechanical demand	1.Solder temperture:240±2°C			
Solderability	No visible mechanical damage. Wetting shall exceed 75% coverage for.	2.Duration: 3 sec.			
Reference documents:	2. Wetting shall exceed 75% coverage for				
GB/T 2423.28-2005 可焊性试验	3. Terminals must have 95% minimum solder coverage	4.Flux: 25% Resin and 75% ethanol in weight			
1.1 年 17 16/4377	A Property of the second secon	ATT.			



	G)	C C
Items	Requirements	Test Methods and Remarks
Vibration Reference documents: GB/T 2423.10-2019 振動試验	1.No visible mechanical damage. 2. Inductance change: Within ±10%. 3. Q factor change: Within ±20%. Cu pad Solder mask Glass Epoxy Board	1.Solder the inductor to the testing jig (glass epoxy boardshown in) using leadfree solder. 2.The inductor shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the frequency being varieduniformly between the approximate limits of 10 and 55 Hz. 3.The frequency range from 10 to 55 Hz and return to 10 Hz shallbe traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions(total of 6 hours).
SKN-IIII je jihi V		1.Start at (85~125°C) for T time, rush to Zn: (-55~40°C) for T time as one cycle, go through100
Thermal Shock Reference documents:	Within ≦30%) 3.Q factor change: Within ±20%.	cycles. 2.Transforming interval: Max. 20 sec. 3.Tested cycle: 100 cycles.
GB/T 2423.22-2012 Method Na 冷热冲击试验	SKI SKI	4. The chip shall be stabilized at normal condition for 1~2 hours 125 C /85 C Ambient Temperature -55 C /-40 C 20sec. (max.)
Low temperature Storage Reference documents:	 1.No visible mechanical damage. 2. Inductance change: Within ±10%.(Mn-Zn: Within ≤30%) 3.Q factor change: Within ±20%. 	1.Temperature:M(-55~-40±2°C) 2.Duration: 96±2 hours 3.The chip shall be stabilized at normal condition for 1~2 hoursbefore measuring.
GB/T 2423.1-2008 Method Ab 低温储存试验	SXNIMIE	Room Temp 0 96H Test 97H 98H Time M.C. Temp

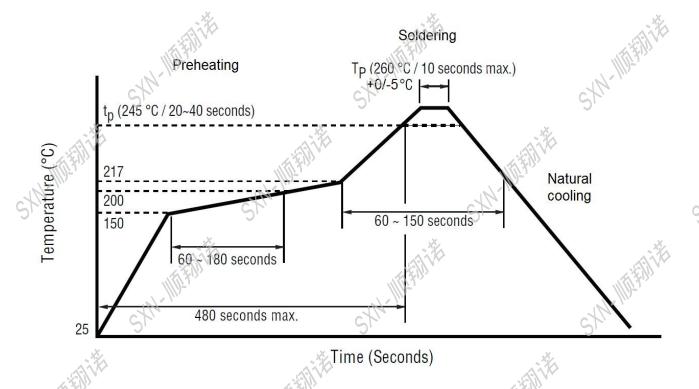


	<u> </u>	<u> </u>			
Items	Requirements	Test Methods and Remarks			
	1.No visible mechanical damage.	1.Temperature:N(125~85±2°ℂ).			
High temperature	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours			
Storage	Within ≦ 30%)	3. The chip shall be stabilized at normal condition			
Reference documents:	3.Q factor change: Within ±20%.	for 1~2 hoursbefore measuring.			
GB/T 2423.2-2008	- **	Temp High temperature			
Method Bb		N.C.			
高温储存试验	11/2/2	Room			
S. 13. 13. 13. 13. 13. 13. 13. 13. 13. 13	gh.	0 96H 97H 98H Time			
	1.No visible mechanical damage.	1.Temperature: 60±2℃			
1	2. Inductance change: Within ±10%.(Mn-Zn:	2.Humidity: 90% to 95% RH.			
Damp Heat	Within ≦ 30%)	3.Duration: 96±2 hours.			
(Steady States)	3.Q factor change: Within ±20%.	4.The chip shall be stabilized at normal condition			
Reference documents:	or sr	for 1~2 hoursbefore measuring.			
GB/T 2423.3-2016	J&.	Temp & Humidity			
恒定湿热试验	· Salata	93%RH High temperature High humidity			
		Room Conditions			
AN-III	M. M.	0 Test 0 96H 97H 98H Time			
Lleat and manage of	1.No significant defects in appearance.	G.N.			
Heat endurance of	2. △ L/L ≤ 10% (Mn-Zn: △ L/L ≤ 30%)	1.Refer to the above reflow curve and go through the reflow for twice.			
Reflow soldering Reference documents:	3. △ Q/Q ≦ 30% (SMD series only)	2.The peak temperature : 260+0/-5℃			
GJB 360B-2009	4. △ DCR/DCR ≦ 10%	2. The peak temperature . 200 · 0/ 0 ©			
回流焊耐热性试验	this this	Mills			
- VIO) PIO / III E II VIO	No case deformation or change in	To dip parts into IPA solvent for 5±0.5Min,then			
Resistance to solvent	appearance or obliteration of marking	drying them at room temp for 5Min,at last ,to			
test		brushing making 10 times.			
Reference documents:	11/2/11/2				
IEC 68-2-45:1993	- XN-1:	M. III			
耐溶剂性试验	Sr	Sr			
	<u> </u>	- X X-			
Overload test	1.During the test no smoke, no peculiar,				
Reference documents:	smell, no fire	D5.,			
JIS C5311-6.13	2.The characteristic is normal after test	Apply twice as rated current for 5 minutes.			
过负荷试验	SI.	Sr.			
voltage resistance test	1.During the test no breakdown				
- × (/l)	2.The characteristic is normal after test				
MIL-STD-202G Method	17-1113-	1. For parts with two coils			
301 5	Sh	2. DC1000V Current: 1mA, Time: 1Min.			
绝缘耐压测试	JX.	Refer to catalogue of specific products			
*		A TOP			



◆推荐回流焊温度曲线

Recommended reflow soldering curve:



The recommended reflow conditions as above graph, is set according to our soldering equipment. DUE to various manufactures may have different reflow soldering equipment, products, process conditions, set methods. And so on, when setting the reflow conditions, Please adjust and confirm according to users' environment/equipment.

SXN-IIIIi ji ji ji ji

SM-IIII



使用注意事项

REMINDERS FOR USING THESE PRODUCTS



● 保存时间为12 个月以内,保存条件(温度5~40°C以下、湿度35 ~ 66%RH 以下),需充分注意。若超过保存时间,端子电极的可焊性将可能老化。

The storage period is within 12 months. Be sure to follow the storage conditions (temperature: $5\sim40^{\circ}$ C, humidity: 35 to 65% RH or less). If the storage period elapses, the soldering of the terminal electrodes may deteriorate.

• 请勿在气体腐蚀环境(盐、酸、碱等)下使用和保存。

Do not use or store in locations where there are conditions such as gas corrosion (salt, acid, alkali, etc.).

• 手上的油脂会导致可焊性降低,应避免用手直接接触端子。

Don't touch electrodes directly with bare hands as oil secretions may inhibit soldering Always ensure optimum conditions for soldering.

请小心轻拿轻放,避免由于产品的跌落或取出不当而导致的损坏。

Please always handle products carefully to prevent any damage caused bydropping down or inappropriate removing.

• 端子过度弯曲会导致断线,请不要过度弯曲端子。

Don't bend the terminals with excessive stress in case of any wire fracture.

• 不要清洗产品, 如需要清洗时请联系我司。

Don't rinse coils by yourself and please contact SXN if necessary.

• 请勿将本产品靠近磁铁或带有磁力的物体

Don't expose the products to magnets or magnetic fields

- 在实施焊接前,请务必进行预热。预热温度与焊接温度及芯片温度的温度差要在150°C 以内。
 Before soldering, be sure to preheat components. The preheating temperature should be set so that the temperature difference between the solder temperature and chip temperature does not exceed 150°C.
- 安装后的焊接修正应在规格书规定的条件范围内。若加热过度可能导致短路、性能降低、寿命减少。 Soldering corrections after mounting should be within the range of the conditions determined in the specifications. If overheated, a short circuit, performance deterioration, or lifespan shortening may occur.
- 装置会因通电而自我发热(温度上升),因此在热设计方面需留有充分余地。
 Self heating (temperature increase) occurs when the power is turned ON, so the tolerance should be sufficient for the set thermal design.
- 非磁屏蔽型在基板设计时需注意配置线圈,受到电磁干扰可能会导致误动作。
 Carefully lay out the coil for the circuit board design of the non-magnetic shield type. A malfunction may occur due to magnetic interference.
- 当本公司产品使用在一般电子设备以外的场合,如:车载,医疗设备,军用,航空航天等,请务必联繫本公司营业部门, 如超出本公司产品使用条件而引起的机器故障时,本公司概不负责。
 - If SXN product will be applied in area like automotive product, medical equipment, military and aerospace except generalelectronic device, please keep SXN sales informed in advance. SXN shall not be held liable for any malfunction or breakdowncaused by using product in the condition which is inconsistent with that recommended by SXN.